Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/685,600	CHANG ET AL.
Examiner	**Art Unit**
Kin-Chan Chen	1765

SEARCHED

Class	Subclass	Date	Examiner
438	706	5/6/2005	K-cc
	710		
	714		
	719		
	720		
	723		
	724		
	694		
438	700	5/6/05	K-cc

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East key words search USPAT, USPG-pub. EPO, JPO, IBM_TDB.	5/6/05	K-cc
Derwent, Inventor search		